







TLV387 SBOSA91 - DECEMBER 2021

TLVx387 High Precision, Zero-Drift, Low-Input-Bias-Current Op Amps

1 Features

- Ultra-low offset voltage: ±10 µV (maximum)
- Zero drift: ±0.01 µV/°C
- Low-input bias current: 300 pA (maximum)
- Low noise: 8.5 nV/√Hz at 1 kHz
- No 1/f noise: 177 nV_{PP} (0.1 Hz to 10 Hz)
- Common-mode input range ±100 mV beyond supply rails
- Gain bandwidth: 5.7 MHz
- Quiescent current: 570 µA per amplifier
- Single supply: 1.7 V to 5.5 V Dual supply: ±0.85 V to ±2.75 V
- EMI and RFI filtered inputs

2 Applications

- Electronic thermometer
- Weigh scale
- Temperature transmitter
- Ventilators
- Data acquisition (DAQ)
- Semiconductor test
- Lab and field instrumentation
- Merchant network and server PSU
- Analog input module
- Pressure transmitter

3 Description

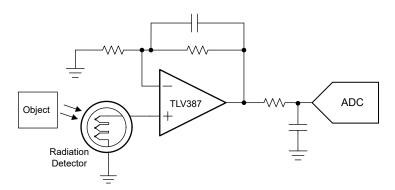
The TLV387, TLV2387, and TLV4387 (TLVx387) family of precision amplifiers offers state-of-the-art performance. With zero-drift technology, the TLVx387 offset voltage and offset drift provide unparalleled long-term stability. With a mere 570 µA of quiescent current, the TLVx387 are able to achieve 5.7 MHz of bandwidth, a broadband noise of 8.5 nV/ \sqrt{Hz} , and a 1/f noise at 177 nV_{PP}. These specifications are crucial to achieve extremely-high precision and no degradation of linearity in 16-bit to 24-bit analog to digital converters (ADCs). The TLVx387 feature flat bias current over temperature; therefore, little to no calibration is needed in high input impedance applications over temperature.

All versions are specified over the temperature range of -40°C to +125°C.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)		
TLV387	SOT-23 (5)	2.90 mm × 1.60 mm		
TLV2387 (2)	VSSOP (8)	3.00 mm × 3.00 mm		
TLV4387 (2)	TSSOP (14)	5.00 mm × 4.40 mm		

- For all available packages, see the package option (1) addendum at the end of the data sheet.
- Device is preview.



The TLV387 as a Precision, Low-Noise ADC Driver



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4 Revision History

DATE	REVISION	NOTES
December 2021	*	Initial Release



5 Pin Configuration and Functions

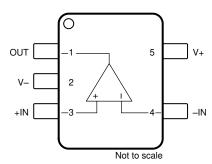


Figure 5-1. DBV (5-Pin SOT-23) Package, Top View

Table 5-1. Pin Functions

P	PIN		DESCRIPTION		
NAME	NO.	TYPE	DESCRIPTION		
-IN	4	Input	Inverting input		
+IN	3	Input	Noninverting input		
OUT	1	Output	Output		
V-	2	Power	Negative (lowest) power supply		
V+	5	Power	Positive (highest) power supply		



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

	1 5 1 5		MIN	MAX	UNIT	
\/	Supply Voltage V = (V+) (V)	Single-supply		6	V	
Vs	Supply Voltage, $V_S = (V+) - (V-)$	Dual-supply		±3	V	
	Input voltage all pine	Common-mode	(V-) - 0.5	(V+) + 0.5	V	
	Input voltage, all pins	Differential		(V+) – (V–) + 0.2		
	Input current, all pins			±10	mA	
	Output short circuit ⁽²⁾		Continuous	Continuous		
T _A	Operating temperature		-55	150	°C	
TJ	Junction temperature		-55	150	°C	
T _{stg}	Storage temperature		-65	150	°C	

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾		V
V _(ESD)	Liectrostatic discharge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±1000	v

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM MAX	UNIT
Cumhusaltaga V = (VL) (V)		Single-supply	1.7	5.5	V
Vs	Supply voltage, $V_S = (V+) - (V-)$	Dual-supply	±0.85	±2.75	V
T _A	Specified temperature		-40	125	°C

6.4 Thermal Information

		TLV387	
	THERMAL METRIC(1)	DBV (SOT-23)	UNIT
		5 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	187.1	°C/W
R _{0JC(top)}	Junction-to-case(top) thermal resistance	107.4	°C/W
R _{θJB}	Junction-to-board thermal resistance	57.5	°C/W
ΨЈТ	Junction-to-top characterization parameter	33.5	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	57.1	°C/W
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

Product Folder Links: TLV387

⁽²⁾ Short-circuit to ground, one amplifier per package.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.5 Electrical Characteristics

at T_A = 25°C, R_L = 10 k Ω connected to V_S / 2, V_S = 1.7 V to 5.5 V, V_{CM} = V_S / 2, V_{OUT} = V_S / 2, and min and max specification established from manufacturing final test (unless otherwise noted)

	PARAMETER	TEST C	ONDITIONS	MIN	TYP	MAX	UNIT
OFFSET V	OLTAGE						
		V _S = 5.5 V			±1	±5	μV
V _{OS}	Input offset voltage	V _S = 1.7 V			±1.25 ±6		
dV _{OS} /dT	Input offset voltage drift	$T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}^{(1)}$			±0.01	±0.05	μV/°C
	Power supply rejection				±0.05	±0.5	
PSRR	ratio	$T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}^{(1)}$				±1	μV/V
INPUT BIA	AS CURRENT	I					
					±60	±300	
l _B	Input bias current	$T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}^{(1)}$				±350	pA
					±60	±500	
I _{OS}	Input offset current	$T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}^{(1)}$,	±700	pA
NOISE					,		
		6 0 4 11 1 40 11			177		nV _{PP}
	Input voltage noise	f = 0.1 Hz to 10 Hz			27		nV_{RMS}
		f = 1 Hz			8.5		
		f = 10 Hz			8.5		->///
e _N	Input voltage noise density	f = 100 Hz			8.5		nV/√ Hz
		f = 1 kHz			8.5		
i _N	Input current noise	f = 1 kHz			70		fA/√Hz
INPUT VO	LTAGE						
.,	Common-mode voltage	V _S = 1.7 V		(V-) - 0.1		(V+)	V
V _{CM}	range	V _S = 5.5 V	(V-) - 0.2		(V+) + 0.1	V	
		$(V-) - 0.1 V < V_{CM} < (V+), V$	V _S = 1.7 V	115	138		
	Common-mode rejection	$(V-) - 0.2 V < V_{CM} < (V+) +$	0.1 V, V _S = 5.5 V	130	150		
CMRR	ratio	$(V-) - 0.1 V < V_{CM} < (V+),$	$\Gamma_{A} = -40^{\circ}\text{C to } +125^{\circ}\text{C}^{(1)}$	110	132		dB
		$(V-) - 0.2 V < V_{CM} < (V+) + T_A = -40$ °C to +125°C(1)	0.1, V _S = 5.5 V,	130			
INPUT CA	PACITANCE						
Z _{ID}	Differential				100 3		MΩ pF
Z _{ICM}	Common-mode				60 3		GΩ pF
OPEN-LO	OP GAIN						
		(V–) + 100 mV < V _{OUT} <		120	145		
_		(V+) – 100 mV	$T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}^{(1)}$	115			
A _{OL}	Open-loop voltage gain	(V–) + 150 mV < V _{OUT} <		120	145		dB
AOL .		(V+) – 150 mV,				1	



6.5 Electrical Characteristics (continued)

at T_A = 25°C, R_L = 10 k Ω connected to V_S / 2, V_S = 1.7 V to 5.5 V, V_{CM} = V_S / 2, V_{OUT} = V_S / 2, and min and max specification established from manufacturing final test (unless otherwise noted)

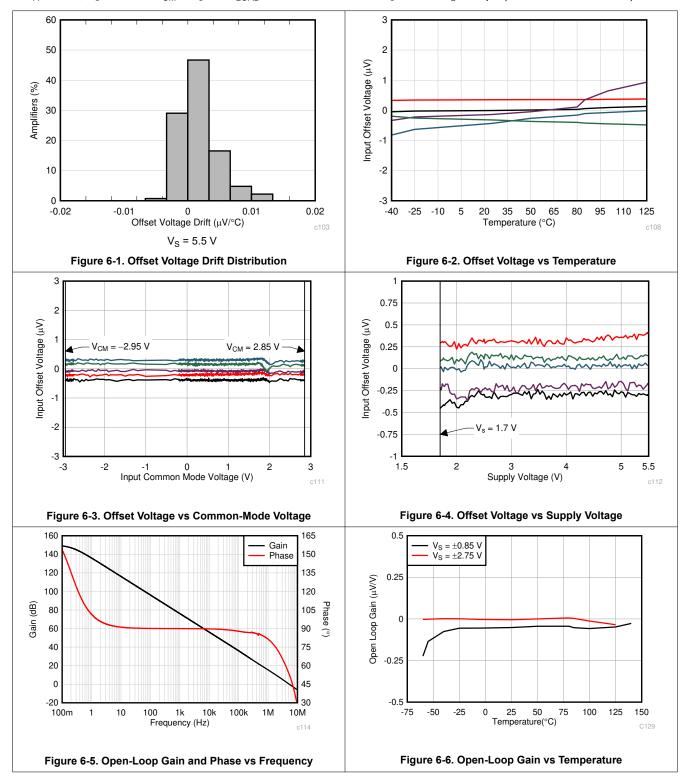
	PARAMETER	TES	ST CONDITIONS	MIN	TYP	MAX	UNIT	
FREQUEN	ICY RESPONSE							
GBW	Gain-bandwidth product				5.7		MHz	
SR	Slew rate	4-V step, G = +1			2.8		V/µs	
	0 1111 11	To 0.1%, 1-V step , G :	= +1		1.5			
t _S	Settling time	To 0.01%, 1-V step , G	G = +1		2.5		μs	
	Overload recovery time	V _{IN} × G > V _S			500		ns	
	Chopping clock frequency ⁽¹⁾			100	150		kHz	
THD+N	Total harmonic distortion + noise	V _{OUT} = 1 V _{RMS} , G = +1	1, f = 1 kHz, R _L = 10 kΩ		0.002 %			
OUTPUT	-							
		no load			1	20		
	Voltage output swing from				5	30	mV	
	rail	$R_L = 2 k\Omega$			20	75	IIIV	
		$T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}$	(1)			30		
	High linearity output swing	A > 100 dD		(V-) + 0.075	(\	/+) – 0.075	V	
	range ⁽¹⁾	A _{OL} > 120 dB	$R_L = 2 k\Omega$	(V-) + 0.150	(\	/+) – 0.150	V	
	Short-circuit current	V _S = 5.5 V			±55		A	
I _{SC}	Short-circuit current	V _S = 1.7 V		±15		mA		
	Phase margin	C _L = 100 pF, G = +1			40		degrees	
POWER S	UPPLY	•						
1	Quiescent current per	1 = 0 mA			570	675	μA	
IQ	amplifier	I _O = 0 mA	$T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}^{(1)}$			700	μA	
	Turn-on time	$V_S = 5.5 \text{ V},$ $V_S \text{ ramp rate > 0.3 V/}\mu$	us, settle to 1%		25	100	μs	

⁽¹⁾ Specification established from device population bench system measurements across multiple lots.



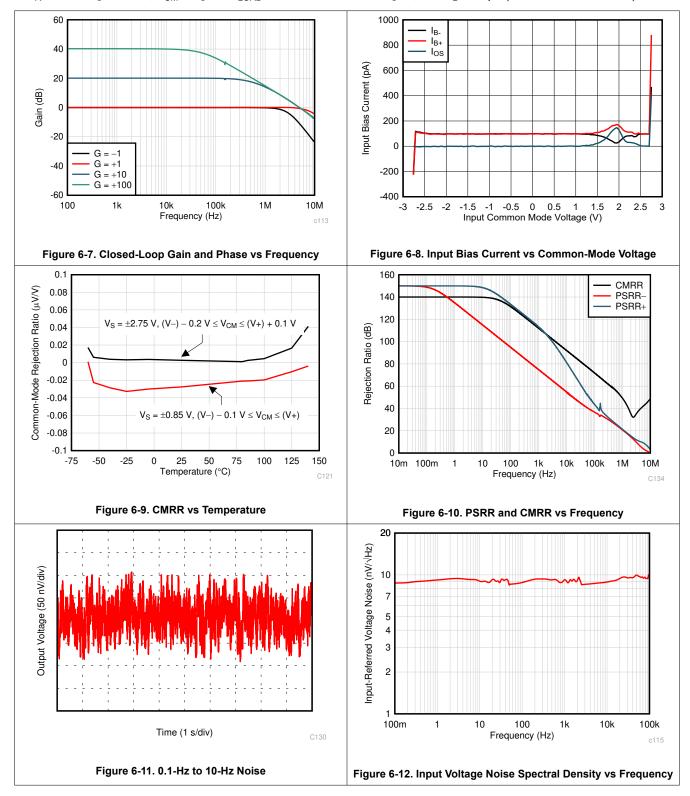
6.6 Typical Characteristics

at T_A = 25°C, V_S = ±2.5 V, V_{CM} = V_S / 2, R_{LOAD} = 10 k Ω connected to V_S / 2, and C_L = 50 pF (unless otherwise noted)



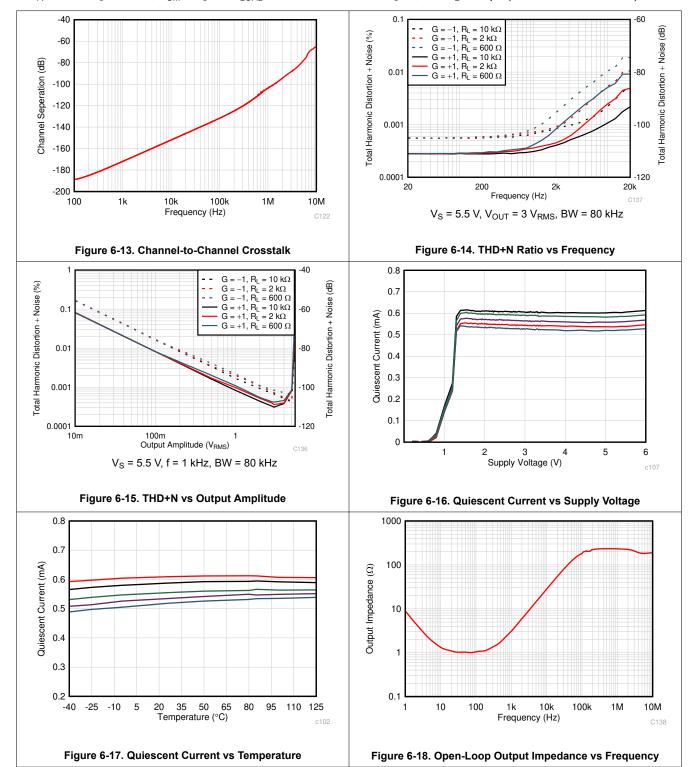


at $T_A = 25$ °C, $V_S = \pm 2.5$ V, $V_{CM} = V_S / 2$, $R_{LOAD} = 10$ k Ω connected to $V_S / 2$, and $C_L = 50$ pF (unless otherwise noted)



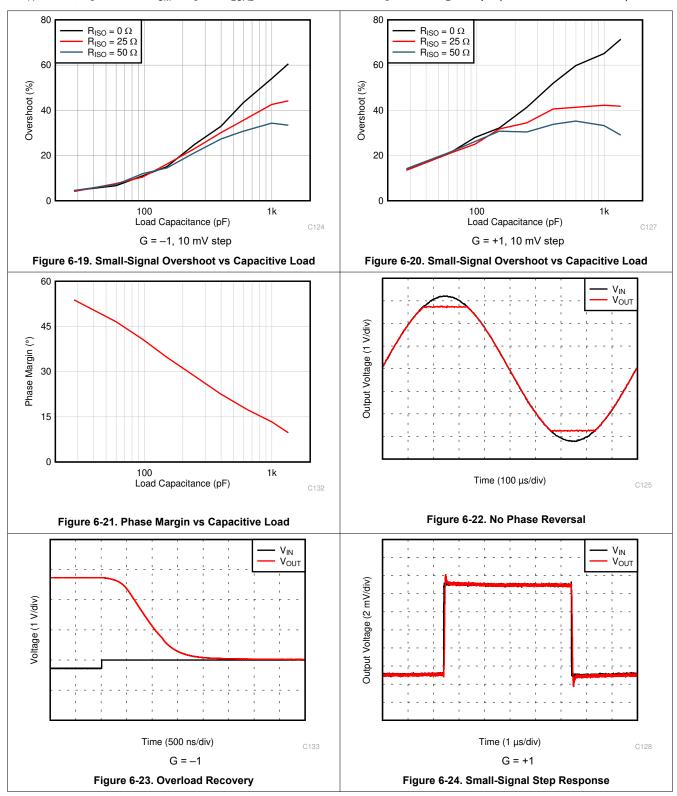


at $T_A = 25^{\circ}C$, $V_S = \pm 2.5$ V, $V_{CM} = V_S / 2$, $R_{LOAD} = 10$ k Ω connected to $V_S / 2$, and $C_L = 50$ pF (unless otherwise noted)



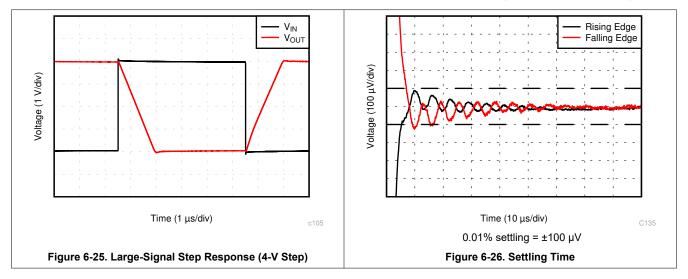


at $T_A = 25$ °C, $V_S = \pm 2.5$ V, $V_{CM} = V_S / 2$, $R_{LOAD} = 10$ k Ω connected to $V_S / 2$, and $C_L = 50$ pF (unless otherwise noted)





at T_A = 25°C, V_S = ±2.5 V, V_{CM} = V_S / 2, R_{LOAD} = 10 k Ω connected to V_S / 2, and C_L = 50 pF (unless otherwise noted)



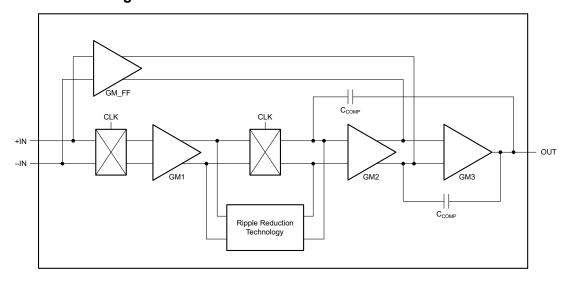


7 Detailed Description

7.1 Overview

The TLVx387 family of zero-drift amplifiers is engineered with state-of-the-art, proprietary, precision zero-drift technology. These amplifiers offer ultra-low input offset voltage and drift, and achieve excellent input and output dynamic linearity. The TLVx387 operate from 1.7 V to 5.5 V, are unity-gain stable, and are designed for a wide range of general-purpose and precision applications. The TLVx387 strengths also include a 5.7-MHz bandwidth, 8.5-nV/\hdot Hz noise spectral density, and no 1/f noise, making the TLVx387 an excellent choice for interfacing with sensor modules, and buffering high-fidelity, digital-to-analog converters (DACs).

7.2 Functional Block Diagram





7.3 Feature Description

7.3.1 Input Bias Current

During normal operation, the typical input bias current of the TLVx387 is 30 pA. The device exhibits low drift over the full temperature range of –40°C to +125°C. There are no antiparallel diodes between the input pins (+IN and –IN); therefore, the differential input maximum voltage is limited only by diodes connected to the supply voltage pins. However, use caution in cases where the input differential voltage exceeds the nominal operating input differential voltage. When inputs are separated, the switching offset-cancellation path internal to the amplifier exceeds normal operating conditions, and can potentially create long settling behavior upon return to normal operation. The equivalent input circuit of TLVx387 is shown in Figure 7-1.

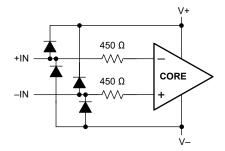


Figure 7-1. Equivalent Input Circuit

7.3.2 EMI Susceptibility and Input Filtering

Operational amplifiers can exhibit sensitivity to electromagnetic interference (EMI). Typically, conducted EMI (that is, EMI that enters the device through conduction) is more commonly observed than radiated EMI (that is, EMI that enters the device through radiation). When conducted EMI enters the operational amplifier, the dc offset at the amplifier output can shift from the nominal value. This shift is a result of signal rectification associated with the internal semiconductor junctions. Although all operational amplifier pin functions can be affected by EMI, the input pins are likely to be the most susceptible. The TLVx387 operational amplifier family incorporates an internal input low-pass filter that reduces the amplifier response to EMI. Both common-mode and differential-mode filtering are provided by the input filter. The conducted EMI rejection of the TLVx387 is seen in Figure 7-2.

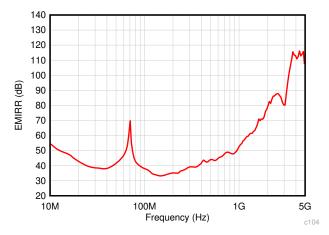


Figure 7-2. EMI Rejection Ratio

7.4 Device Functional Modes

The TLVx387 have a single functional mode and are operational when the power-supply voltage is greater than $1.7 \text{ V} (\pm 0.85 \text{ V})$. The maximum specified power-supply voltage for the TLVx387 is $5.5 \text{ V} (\pm 2.75 \text{ V})$.



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The TLVx387 are unity-gain stable, precision, operational amplifiers featuring state-of-the-art, zero-drift technology. The use of proprietary zero-drift circuitry gives the benefit of low input offset voltage over time and temperature, as well as lower 1/f noise component. As a result of the high PSRR, the devices work well in applications that run directly from battery power without regulation. The TLVx387 family is optimized for full rail-to-rail input, allowing for low-voltage, single-supply operation or split-supply use. These miniature, high-precision, low-noise amplifiers offer high-impedance inputs that have a common-mode range 100 mV beyond the supplies without input crossover distortion, and a rail-to-rail output that swings within 5 mV of the supplies under normal test conditions. The TLVx387 precision amplifiers are designed for upstream analog signal-chain applications in low or high gains, as well as downstream signal-chain functions, such as DAC buffering.

8.1.1 Zero-Drift Clocking

The TLVx387 use an advanced zero-drift architecture to achieve ultra-low offset and offset drift. This architecture uses a clock and switches internally to create a dc error-correction path. The clocking is filtered internally, and typically not observable for most configurations. Take the following precautions to minimize clock noise in the signal chain. The clocking creates a small charge-injection pulse at the input of the amplifier; therefore, do not use high-value resistors (> 100 k Ω) in series with the inputs to avoid higher clock voltage noise at the output. The charge injection pulses are minimized when the impedance to the input pins is matched. If higher value resistors are used, then use matching impedances on both amplifier input pins.

8.2 Typical Applications

8.2.1 Bidirectional Current Sensing

This single-supply, low-side, bidirectional current-sensing design example detects load currents from -1 A to +1 A. The single-ended output spans from 110 mV to 3.19 V. This design uses the TLVx387 because of the device low offset voltage and rail-to-rail input and output. One of the amplifiers is configured as a difference amplifier and the other amplifier provides the reference voltage. Figure 8-1 shows the design example schematic.

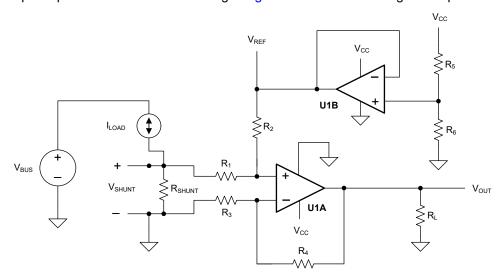


Figure 8-1. Bidirectional Current-Sensing Schematic

Product Folder Links: T/ V387



8.2.1.1 Design Requirements

This solution has the following requirements:

Supply voltage: 3.3 VInput: -1 A to +1 A

Output: 1.65 V ±1.54 V (110 mV to 3.19 V)

8.2.1.2 Detailed Design Procedure

The load current, I_{LOAD} , flows through the shunt resistor, R_{SHUNT} , to develop the shunt voltage, V_{SHUNT} . The shunt voltage is then amplified by the difference amplifier consisting of U1A and R_1 through R_4 . The gain of the difference amplifier is set by the ratio of R_4 to R_3 . To minimize errors, set $R_2 = R_4$ and $R_1 = R_3$. The reference voltage, V_{REF} , is supplied by buffering a resistor divider using U1B. The transfer function is given by Equation 1.

$$V_{OUT} = V_{SHUNT} \times Gain_{Diff_Amp} + V_{REF}$$
 (1)

where

•
$$V_{SHUNT} = I_{LOAD} \times R_{SHUNT}$$

Gain_{Diff_Amp} =
$$\frac{R_4}{R_3}$$

$$V_{REF} = V_{CC} \times \left[\frac{R_6}{R_5 + R_6} \right]$$

There are two types of errors in this design: gain and offset. Gain errors are introduced by the tolerance of the shunt resistor and the ratios of R_4 to R_3 and, similarly, R_2 to R_1 . Offset errors are introduced by the voltage divider (R_5 and R_6) and how closely the ratio of R_4 / R_3 matches R_2 / R_1 . The latter value affects the CMRR of the difference amplifier, ultimately translating to an offset error.

The value of V_{SHUNT} is the ground potential for the system load because V_{SHUNT} is a low-side measurement. Therefore, a maximum value must be placed on V_{SHUNT} . In this design, the maximum value for V_{SHUNT} is set to 100 mV. Equation 2 calculates the maximum value of the shunt resistor given a maximum shunt voltage of 100 mV and maximum load current of 1 A.

$$R_{SHUNT(Max)} = \frac{V_{SHUNT(Max)}}{I_{LOAD(Max)}} = \frac{100 \text{ mV}}{1 \text{ A}} = 100 \text{ m}\Omega$$
(2)

The tolerance of R_{SHUNT} is directly proportional to cost. For this design, a shunt resistor with a tolerance of 0.5% is selected. If greater accuracy is required, select a 0.1% resistor or better.

The load current is bidirectional; therefore, the shunt voltage range is -100 mV to +100 mV. This voltage is divided down by R_1 and R_2 before reaching the operational amplifier, U1A. Make sure that the voltage present at the noninverting node of U1A is within the common-mode range of the device. Use an operational amplifier, such as the TLVx387, that has a common-mode range that extends below the negative supply voltage. The offset error is minimal because the TLVx387 has a typical offset voltage of merely $\pm 0.25 \ \mu V$ ($\pm 5 \ \mu V$, maximum).

Given a symmetric load current of -1 A to +1 A, the voltage divider resistors, R_5 and R_6 , must be equal. To be consistent with the shunt resistor, a tolerance of 0.5% is selected. To minimize power consumption, $10-k\Omega$ resistors are used.

To set the gain of the difference amplifier, the common-mode range and output swing of the TLVx387 must be considered. Equation 3 and Equation 4 depict the typical common-mode range and maximum output swing, respectively, of the TLVx387 given a 3.3-V supply.

$$-100 \text{ mV} < V_{CM} < 3.4 \text{ V}$$
 (3)

$$100 \text{ mV} < V_{\text{OUT}} < 3.2 \text{ V}$$
 (4)



The gain of the difference amplifier can now be calculated as shown in Equation 5.

$$Gain_{Diff_Amp} = \frac{V_{OUT_Max} - V_{OUT_Min}}{R_{SHUNT} \times (I_{MAX} - I_{MIN})} = \frac{3.2 \text{ V} - 100 \text{ mV}}{100 \text{ m}\Omega \times [1 \text{ A} - (-1 \text{A})]} = 15.5 \frac{\text{V}}{\text{V}}$$
(5)

The resistor value selected for R_1 and R_3 is 1 k Ω . 15.4 k Ω is selected for R_2 and R_4 because this number is the nearest standard value. Therefore, the ideal gain of the difference amplifier is 15.4 V/V.

The gain error of the circuit primarily depends on R_1 through R_4 . As a result of this dependence, 0.1% resistors were selected. This configuration reduces the likelihood that the design requires a two-point calibration. A simple one-point calibration, if desired, removes the offset errors introduced by the 0.5% resistors.

8.2.1.3 Application Curve

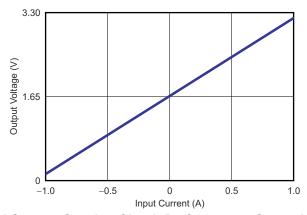


Figure 8-2. Bidirectional Current-Sensing Circuit Performance: Output Voltage vs Input Current

8.2.2 Load Cell Measurement

Figure 8-3 shows the TLVx387 in a high-CMRR dual-op amp instrumentation amplifier with a trim resistor and six-wire load cell for precision measurement.

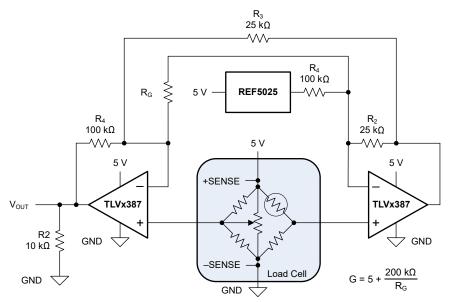


Figure 8-3. Load Cell Measurement Schematic



9 Power Supply Recommendations

The TLVx387 family of devices is specified for operation from 1.7 V to 5.5 V for single supplies, and ± 0.85 V to ± 2.75 V for dual supplies. Key parameters that can exhibit significant variance with regard to operating voltage are presented in Section 6.6.

CAUTION

Supply voltages greater than 6 V can permanently damage the device (see Section 6.1).

10 Layout

10.1 Layout Guidelines

Pay attention to good layout practice. Keep traces short and, when possible, use a printed-circuit board (PCB) ground plane with surface-mount components placed as close to the device pins as possible. Place a 0.1-µF capacitor close to the supply pins. These guidelines must be applied throughout the analog circuit to improve performance, and provide benefits such as reducing the electromagnetic interference (EMI) susceptibility.

For lowest offset voltage and precision performance, optimize circuit layout and mechanical conditions. Avoid temperature gradients that create thermoelectric (Seebeck) effects in the thermocouple junctions formed from connecting dissimilar conductors. Cancel these thermally-generated potentials by making sure that the potentials are equal on both input pins. Other layout and design considerations include:

- · Use low thermoelectric-coefficient conditions (avoid dissimilar metals).
- Thermally isolate components from power supplies or other heat sources.
- · Shield operational amplifier and input circuitry from air currents, such as cooling fans.

Follow these guidelines to reduce the likelihood of junctions being at different temperatures, which can cause thermoelectric voltage drift of $0.1~\mu\text{V}/^{\circ}\text{C}$ or higher depending on materials used.

10.2 Layout Example

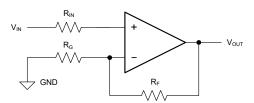


Figure 10-1. Schematic Representation

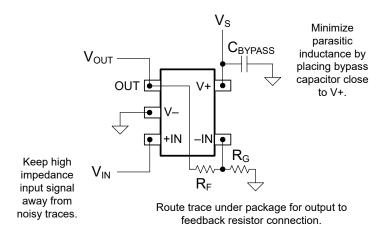


Figure 10-2. Layout Example



11 Device and Documentation Support

11.1 Device Support

11.1.1 Development Support

11.1.1.1 PSpice® for TI

PSpice® for TI is a design and simulation environment that helps evaluate performance of analog circuits. Create subsystem designs and prototype solutions before committing to layout and fabrication, reducing development cost and time to market.

11.1.1.2 TINA-TI™ Simulation Software (Free Download)

TINA-TI™ simulation software is a simple, powerful, and easy-to-use circuit simulation program based on a SPICE engine. TINA-TI simulation software is a free, fully-functional version of the TINA™ software, preloaded with a library of macromodels, in addition to a range of both passive and active models. TINA-TI simulation software provides all the conventional dc, transient, and frequency domain analysis of SPICE, as well as additional design capabilities.

Available as a free download from the Analog eLab Design Center, TINA-TI simulation software offers extensive post-processing capability that allows users to format results in a variety of ways. Virtual instruments offer the ability to select input waveforms and probe circuit nodes, voltages, and waveforms, creating a dynamic quick-start tool.

Note

These files require that either the TINA software or TINA-TI software be installed. Download the free TINA-TI simulation software from the TINA-TI™ software folder.

11.2 Documentation Support

11.2.1 Related Documentation

For related documentation see the following: Texas Instruments, Circuit board layout techniques

11.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.4 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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11.5 Trademarks

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11.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.



11.7 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLV387DBVR	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	SN	Level-2-260C-1 YEAR	-40 to 125	2LOT	Samples
TLV387DBVT	ACTIVE	SOT-23	DBV	5	250	RoHS & Green	SN	Level-2-260C-1 YEAR	-40 to 125	2LOT	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV387DBVR	SOT-23	DBV	5	3000	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3
TLV387DBVT	SOT-23	DBV	5	250	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV387DBVR	SOT-23	DBV	5	3000	190.0	190.0	30.0
TLV387DBVT	SOT-23	DBV	5	250	190.0	190.0	30.0



SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Refernce JEDEC MO-178.

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
- 5. Support pin may differ or may not be present.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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